

**Method 1033**

New method proposed by industry. Evaluates the electrical stability of DUT.

**1018.1**

Major rewrite to increase repeatability. Proposed by test equipment manufactures

**1071.7**

New failure criteria paragraphs 8.2.1.1, 8.2.1.2, 8.2.1.3. Major addition.

TABLE 1071-V. Fixed conditions for test condition H<sub>1</sub>: Reject limit changed from  $5 \times 10^{-6}$  to  $5 \times 10^{-8}$   
Proposed by industry.

**2069.2**

Paragraph 3.1c delete high magnification

Paragraphs added 3.4, 3.5 and 4. New failure criteria. Major addition.

Proposed by industry.

**2071.5**

Major rewrite. New failure criteria. Paragraphs added: 3.1.1. 2, through 4.

New figures 2071-9 through 2071-14.

Proposed by industry.

**2073.1**

Major rewrite. New failure criteria. New figures.

Proposed by semiconductor supplier.

**3131.3**

Major rewrite. Statistical approach to thermal characterization.

Proposed by industry.

**3471.2**

Minor changes to 3.1.1.c, 3.2.1.c and 3.1.1.e

Proposed by semiconductor supplier.

**4066.4**

Minor changes. Definitions.

Proposed by industry.